

# IPB80N06S4-05 IPI80N06S4-05, IPP80N06S4-05

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics <sup>2)</sup>						
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	-	1.4	K/W
Thermal resistance, junction - ambient, leaded	$R_{\rm thJA}$	-	-	-	62	
SMD version, device on PCB	$R_{ m thJA}$	minimal footprint	-	-	62	
		6 cm <sup>2</sup> cooling area <sup>3)</sup>	-	-	40	

# **Electrical characteristics,** at $T_{\rm j}$ =25 °C, unless otherwise specified

### **Static characteristics**

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	$V_{\rm GS}$ =0V, $I_{\rm D}$ = 1mA	60	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=60\mu{\rm A}$	2.0	3.0	4.0	
Zero gate voltage drain current	IDSS	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	1	0.01	1	μΑ
		$V_{\rm DS}$ =60V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C <sup>2)</sup>	-	5	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =80A	-	4.7	5.7	mΩ
		$V_{\rm GS}$ =10V, $I_{\rm D}$ =80A, SMD version	-	4.4	5.4	

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			min.	typ.	max.	
Dynamic characteristics <sup>2)</sup>						
Input capacitance	C iss	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1MHz	-	5000	6500	pF
Output capacitance	Coss		-	1230	1600	
Reverse transfer capacitance	C <sub>rss</sub>		-	50	100	
Turn-on delay time	t <sub>d(on)</sub>	$V_{\rm DD}$ =30V, $V_{\rm GS}$ =10V, $I_{\rm D}$ =80A, $R_{\rm G}$ =3.5 $\Omega$	-	20	-	ns
Rise time	t <sub>r</sub>		-	5	-	
Turn-off delay time	$t_{d(off)}$		-	35	-	
Fall time	t <sub>f</sub>		-	8	-	
Gate Charge Characteristics <sup>2)</sup>						
Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =48V, I <sub>D</sub> =80A, V <sub>GS</sub> =0 to 10V	-	28	36	nC
Gate to drain charge	Q <sub>gd</sub>		-	7	14	]
Gate charge total	Qg		-	62	81	
Gate plateau voltage	V <sub>plateau</sub>		-	5.6	-	V
Reverse Diode						
Diode continous forward current <sup>2)</sup>	Is	- Т <sub>С</sub> =25°С	-	-	80	А
Diode pulse current <sup>2)</sup>	I <sub>S,pulse</sub>		-	-	320	
Diode forward voltage	$V_{\mathrm{SD}}$	V <sub>GS</sub> =0V, I <sub>F</sub> =80A, T <sub>j</sub> =25°C	0.6	0.95	1.3	V
Reverse recovery time <sup>2)</sup>	t <sub>rr</sub>	$V_R$ =30V, $I_F$ =80A, $di_F/dt$ =100A/µs	-	36	-	ns
Reverse recovery charge <sup>2)</sup>	Q <sub>rr</sub>	]	-	41	-	nC

<sup>&</sup>lt;sup>1)</sup> Current is limited by bondwire; with an  $R_{\rm thJC}$  = 1.4K/W the chip is able to carry 106A at 25°C.

<sup>&</sup>lt;sup>2)</sup> Specified by design. Not subject to production test.

 $<sup>^{3)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



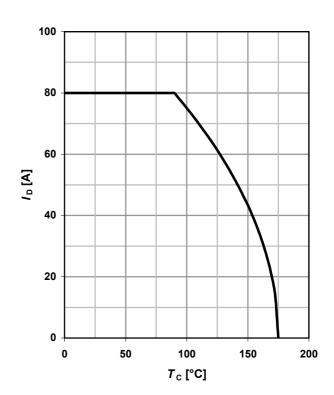
### 1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

# 100 80 80 40 20 0 0 0 50 100 150 200 T<sub>C</sub> [°C]

### 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}; SMD$$



### 3 Safe operating area

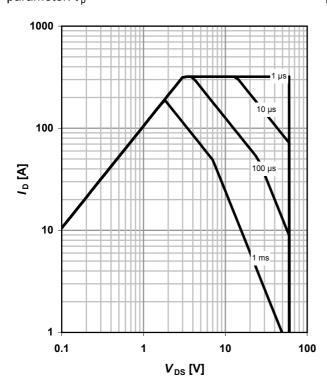
$$I_D = f(V_{DS}); T_C = 25 \degree C; D = 0; SMD$$

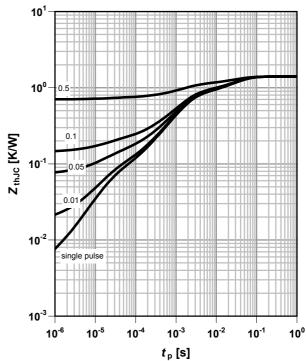
parameter:  $t_p$ 

### 4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter:  $D = t_p/T$ 







### 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C; SMD$ 

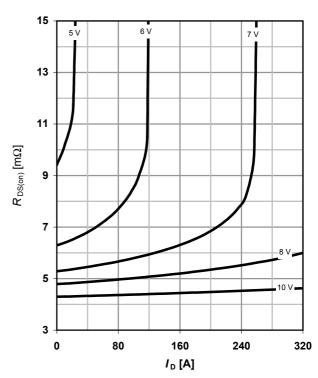
parameter: V<sub>GS</sub>

# 280 240 240 200 120 80 40 0 1 2 3 4 5 6 V<sub>DS</sub> [V]

### 6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 °C; SMD$ 

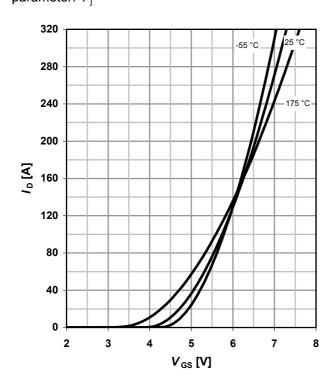
parameter: V<sub>GS</sub>



# 7 Typ. transfer characteristics

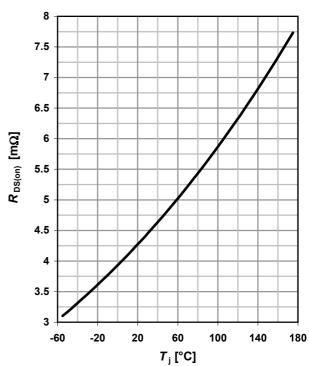
 $I_D = f(V_{GS}); V_{DS} = 6V$ 

parameter: T<sub>i</sub>



### 8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 80 \text{ A}; V_{GS} = 10 \text{ V}; SMD$$





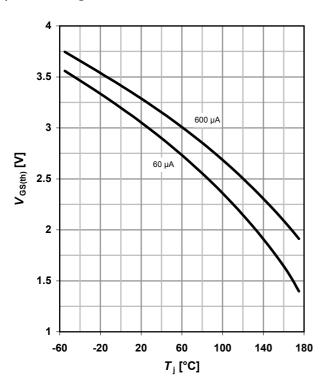
## 9 Typ. gate threshold voltage

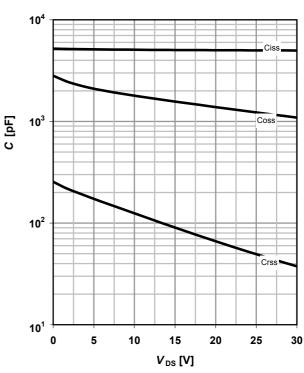
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter:  $I_D$ 

### 10 Typ. capacitances

$$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$$





### 11 Typical forward diode characteristicis

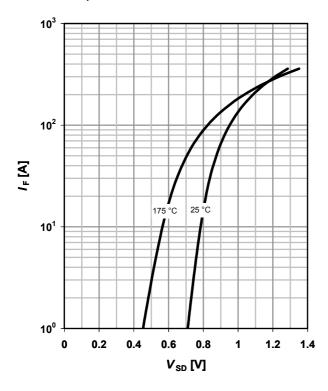
 $IF = f(V_{SD})$ 

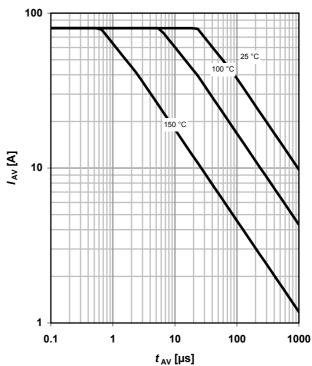
parameter: T<sub>i</sub>

# 12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$ 

parameter: T<sub>i(start)</sub>

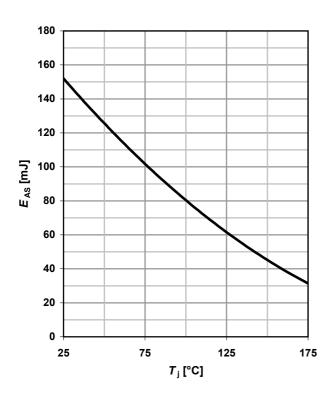






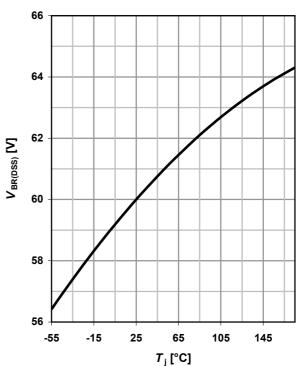
### 13 Avalanche energy

$$E_{AS} = f(T_i); I_D = 40 A$$



### 14 Drain-source breakdown voltage

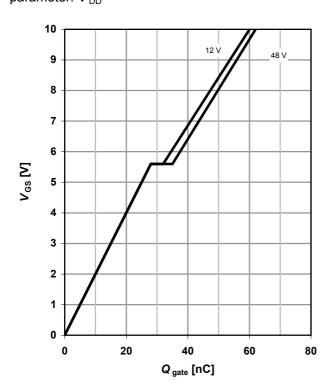
$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$



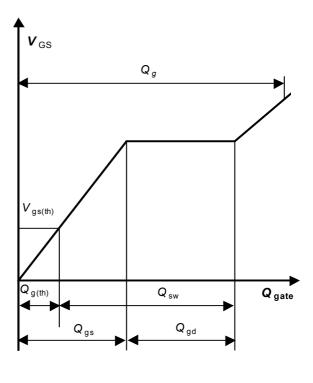
# 15 Typ. gate charge

 $V_{\rm GS}$  = f( $Q_{\rm gate}$ );  $I_{\rm D}$  = 80 A pulsed

parameter: V<sub>DD</sub>



### 16 Gate charge waveforms





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## **Revision History**

Version	Date	Changes		
Revision 1.0	24.03.2009	Final data sheet		